POSTER # 1

SWTest Conference
Memory ProbeCard Test System

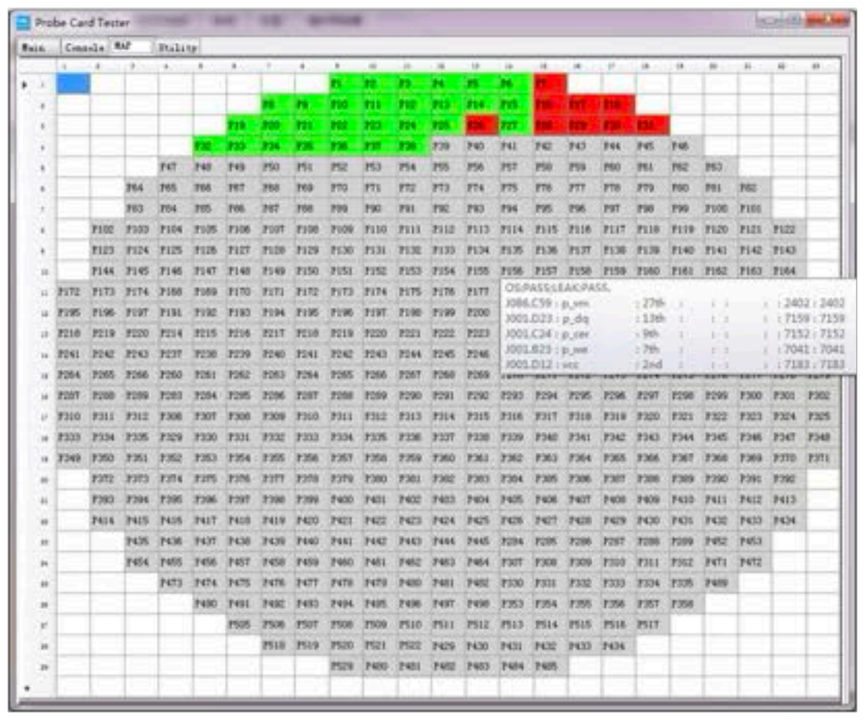
Kenny Song, River Huang
Probing Semiconductor Co.,Ltd

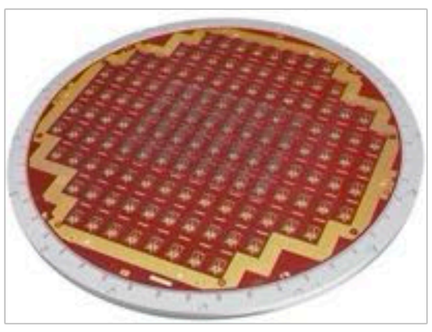
SWTEST
PROBE TODAY, FOR TOMORROW

Probing

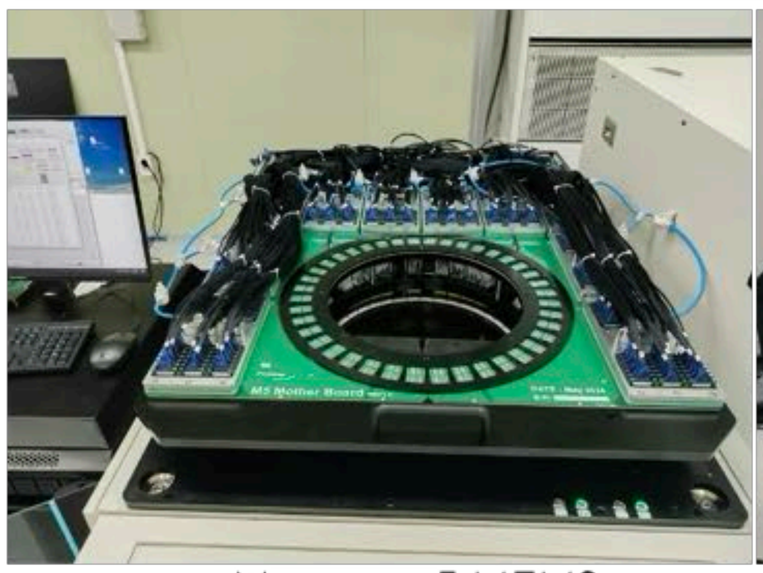
PCT5801
大规模存储器探针卡检测机

ProbeCard TestSystem For Memory





1000KG CHUCK FORCE NEEDLE TIP CAPTURE



Magnum5 MEMS

T5833 32TOM MEMS

T5830 8TOM Cantilever

T5830 T5503 T5833 M5/ND4/93K

POSTER # 2

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PCT5801 Specifications

DC Parametrics

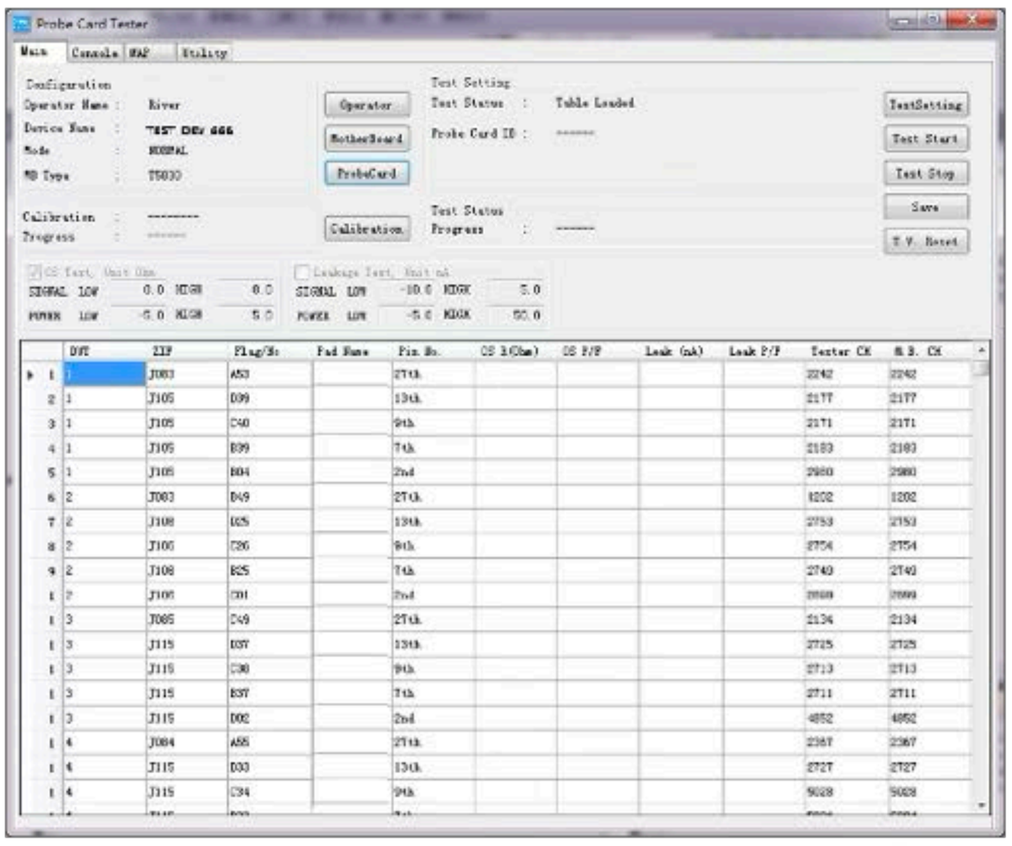
Max Ch	300000 Channels
PMU	1088
Digital	65536 Channels
Driver	200MHz, 1.25v~7V, ±32mA, 128M
Leakage Test	10nA
HV	256 Channels, 13.5V
Cooling	Fan
Interactive UI	JAVA, GUI, Windows, Customize

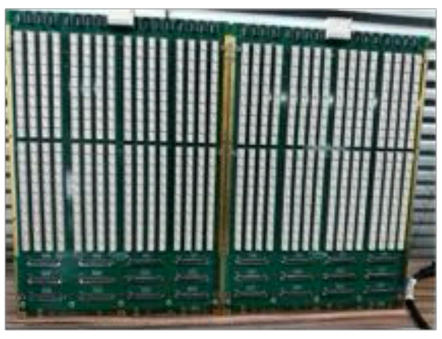
Test Items

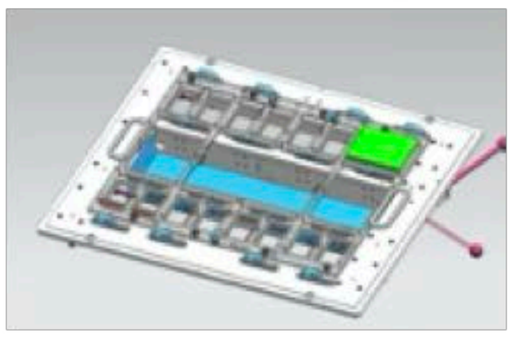
OS	1 min @ 5000 channels
Leakage	15 min @ 5000 channels Pin-to-Pin
Relay Link	1 min
TDR (AC)	35 min , PBDATA matching
Others	64 LBIO Chain (MCW) Control
	FPGA/ASIC Control
Chuck Force	Max 1000kg, tri-temp
Needle Test	2um, TipLength,Alignment,Planarity
NeedTip Inspection	10min@10000pins, 60min@300000pins
Protocal	I2C, SPI, JTAG,GPIB and Any other

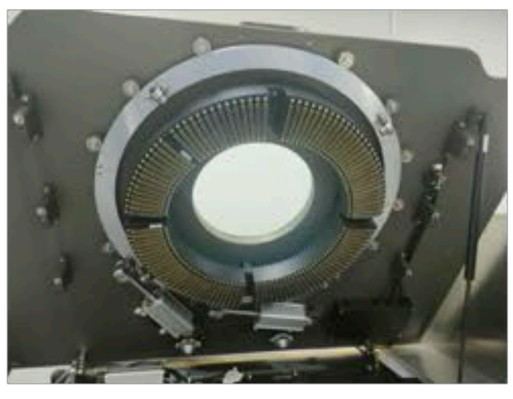
Supported Platforms

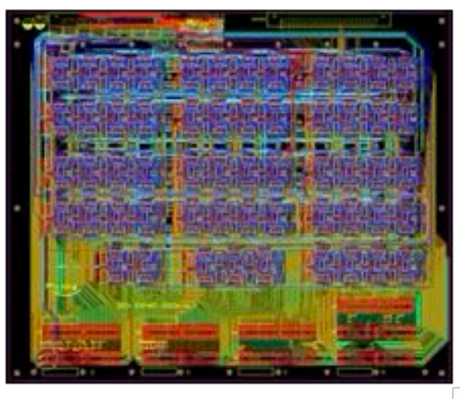
Advantest	T5375 / T5377 / T5377S
	T5830 8/16/26/32 TOM
	T5833
	ND4 / 93KDD
Teradyne	M2
	M5

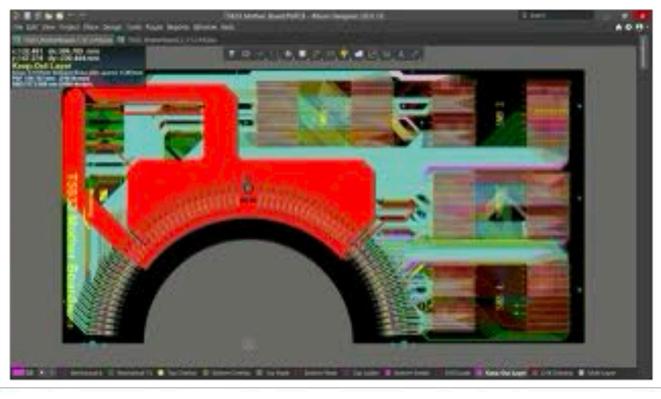












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POSTER # 2

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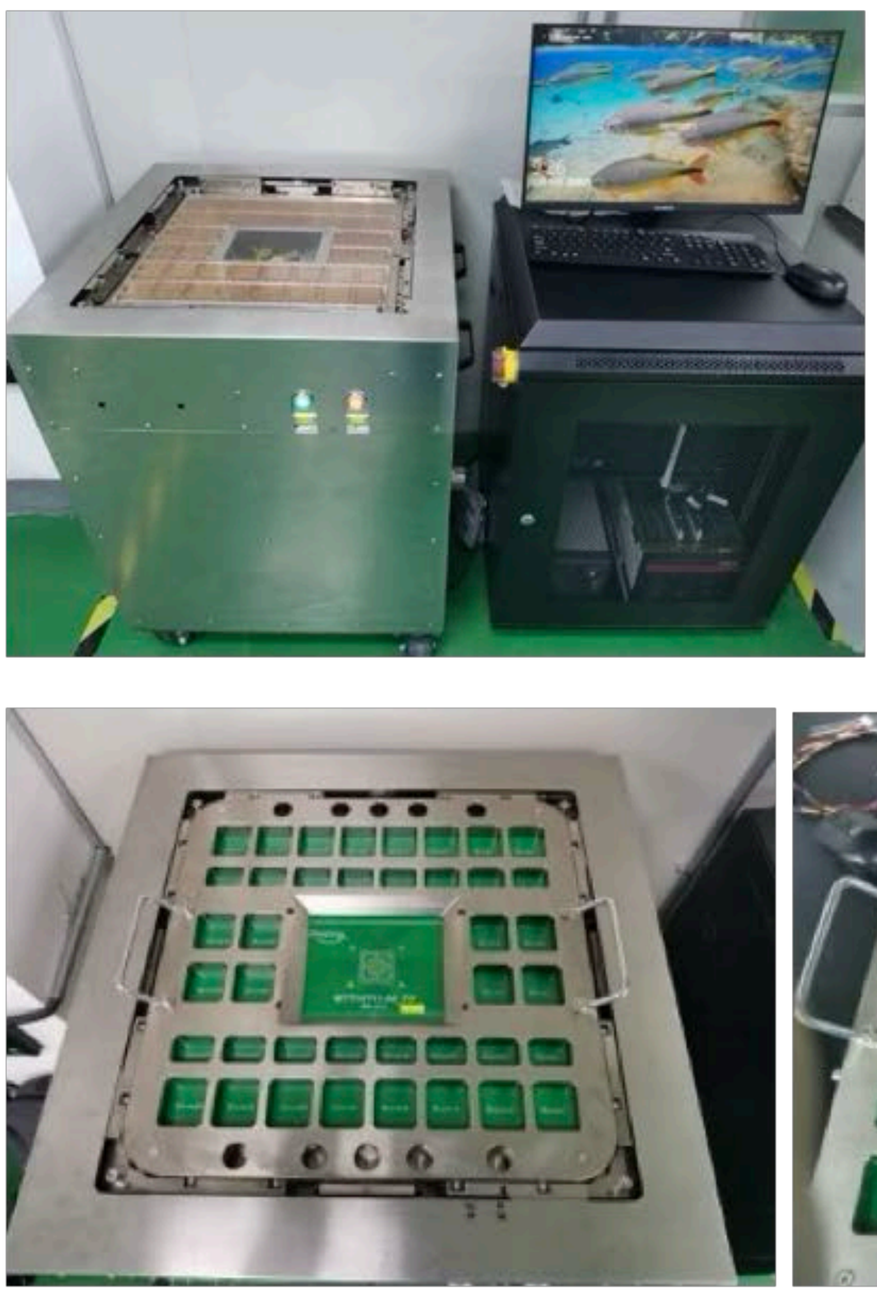
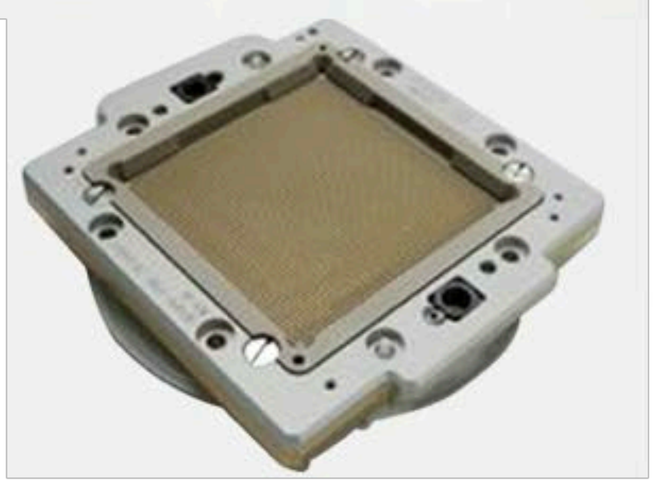
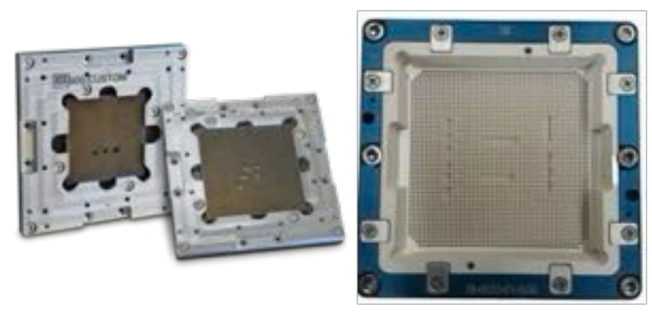
PSTA20K
超大规模针座测试机
Ultra-high Pin-Count Socket Tester



200 Pin Test

8000 Pin Test





5,000 ~ 60,000 PIN AI SOCKET TESTING